

**Integrated circuits - Measurement of electromagnetic immunity - Part 8: Measurement of radiated immunity - IC stripline method**

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## EESTI STANDARDI EESSÕNA

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ICS 31.200

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**Integrated circuits -  
Measurement of electromagnetic immunity -  
Part 8: Measurement of radiated immunity -  
IC stripline method  
(IEC 62132-8:2012)**

Circuits intégrés -  
Mesure de l'immunité électromagnétique -  
Partie 8: Mesure de l'immunité rayonnée -  
Méthode de la ligne TEM à plaques pour  
circuit intégré  
(CEI 62132-8:2012)

Integrierte Schaltungen -  
Messung der elektromagnetischen  
Störfestigkeit -  
Teil 8: Messung der Störfestigkeit bei  
Einstrahlungen -  
IC-Streifenleiterverfahren  
(IEC 62132-8:2012)

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## Foreword

The text of document 47A/882/FDIS, future edition 1 of IEC 62132-8, prepared by SC 47A, "Integrated circuits", of IEC TC 47, "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62132-8:2012.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2013-05-10
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2015-08-10

This standard is to be used in conjunction with EN 62132-1.

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## Endorsement notice

The text of the International Standard IEC 62132-8:2012 was approved by CENELEC as a European Standard without any modification.

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050	Series	International Electrotechnical Vocabulary	-	-
IEC 61000-4-20	2010	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN 61000-4-20	2010
IEC 62132-1	2006	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 62132-1 + corr. November	2006 2006

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# INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC IMMUNITY –

## Part 8: Measurement of radiated immunity – IC stripline method

### 1 Scope

This part of IEC 62132 specifies a method for measuring the immunity of an integrated circuit (IC) to radio frequency (RF) radiated electromagnetic disturbances over the frequency range of 150 kHz to 3 GHz.

### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at <http://www.electropedia.org>)

IEC 62132-1:2006, *Integrated circuits – Measurement of electromagnetic immunity, 150 kHz to 1 GHz – Part 1: General conditions and definitions*

IEC 61000-4-20, *Electromagnetic compatibility (EMC) – Part 4-20: Testing and measurement techniques – Emission and immunity testing in transverse electromagnetic (TEM) waveguides*

### 3 Terms and definitions

For the purpose of this document, the terms and definitions given in IEC 62132-1:2006, Clause 3, IEC 60050-131 and IEC 60050-161, and the following, apply.

#### 3.1

##### transverse electromagnetic mode

##### TEM

waveguide mode in which the components of the electric and magnetic fields in the propagation direction are much less than the primary field components across any transverse cross-section

Note 1 to entry: This note only applies to the French language.

#### 3.2

##### TEM waveguide

open or closed transmission line system, in which a wave is propagating in the transverse electromagnetic mode to produce a specified field for testing purposes

#### 3.3

##### IC stripline

TEM waveguide, consisting of an active conductor placed on a defined spacing over an enlarged ground plane, connected to a port structure on each end and an optional shielded enclosure